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First results on irradiated OVERMOS1, a HR CMOS for HEP applications

Wednesday 22 November 2017 13:00 (20 minutes)

I will present test results of OVERMOS1, a MAPS CMOS detector based on high resistivity substrate. Following a short description of the main features of OVERMOS1 and differences with respect to previous OVERMOS incarnation, I will describe experimental results of test structures, both for standard and neutron irradiated devices, and comparisons with TCAD simulation results.

Authors: VILLANI, Enrico Giulio (STFC-Rutherford Appleton Laboratory (GB)); WILSON, Fergus (STFC-Rutherford Appleton Laboratory (GB)); ZHANG, Zhige (STFC - Rutherford Appleton Lab. (GB)); CHEN, Liejian (Chinese Academy of Sciences (CN)); SEDGWICK, Iain (STFC); DOPKE, Jens (STFC-Rutherford Appleton Laboratory (GB)); WORM, Steven (University of Birmingham); FRENCH, Marcus Julian (STFC - Rutherford Appleton Lab. (GB)); Dr MCMAHON, Stephen (STFC-Rutherford Appleton Laboratory (GB)); SELLER, Paul (RAL); LIANG, Zhijun (Chinese Academy of Sciences (CN)); XIU, Qinglei (Chinese Academy of Sciences (CN)); ZHU, Hongbo (Chinese Academy of Sciences (CN))

Presenter: VILLANI, Enrico Giulio (STFC-Rutherford Appleton Laboratory (GB))

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